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Ophthalmic instruments - Slit-lamp microscopes (ISO 10939:2017)

Táto norma obsahuje anglickú verziu európskej normy.
This standard includes the English version of the European Standard.

Táto norma bola oznámená vo Vestníku ÚNMS SR č. 11/17

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EN ISO 10939

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English Version

Ophthalmic instruments - Slit-lamp microscopes (ISO 10939:2017)

Instruments ophtalmiques - Microscopes avec lampe à fente (ISO 10939:2017)

Ophthalmische Instrumente - Spaltleuchten (ISO 10939:2017)

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EUROPEAN COMMITTEE FOR STANDARDIZATION
COMITÉ EUROPÉEN DE NORMALISATION
EUROPÄISCHES KOMITEE FÜR NORMUNG

CEN-CENELEC Management Centre: Avenue Marnix 17, B-1000 Brussels

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European foreword

This document (EN ISO 10939:2017) has been prepared by Technical Committee ISO/TC 172 "Optics and photonics" in collaboration with Technical Committee CEN/TC 170 "Ophthalmic optics" the secretariat of which is held by DIN.

This European Standard shall be given the status of a national standard, either by publication of an identical text or by endorsement, at the latest by December 2017, and conflicting national standards shall be withdrawn at the latest by December 2017.

Attention is drawn to the possibility that some of the elements of this document may be the subject of patent rights. CEN [and/or CENELEC] shall not be held responsible for identifying any or all such patent rights.

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According to the CEN-CENELEC Internal Regulations, the national standards organizations of the following countries are bound to implement this European Standard: Austria, Belgium, Bulgaria, Croatia, Cyprus, Czech Republic, Denmark, Estonia, Finland, Former Yugoslav Republic of Macedonia, France, Germany, Greece, Hungary, Iceland, Ireland, Italy, Latvia, Lithuania, Luxembourg, Malta, Netherlands, Norway, Poland, Portugal, Romania, Serbia, Slovakia, Slovenia, Spain, Sweden, Switzerland, Turkey and the United Kingdom.

Endorsement notice

The text of ISO 10939:2017 has been approved by CEN as EN ISO 10939:2017 without any modification.

Ophthalmic instruments — Slit-lamp microscopes

Instruments ophtalmiques — Microscopes avec lampe à fente





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ISO copyright office
Ch. de Blandonnet 8 • CP 401
CH-1214 Vernier, Geneva, Switzerland
Tel. +41 22 749 01 11
Fax +41 22 749 09 47
copyright@iso.org
www.iso.org

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Foreword

ISO (the International Organization for Standardization) is a worldwide federation of national standards bodies (ISO member bodies). The work of preparing International Standards is normally carried out through ISO technical committees. Each member body interested in a subject for which a technical committee has been established has the right to be represented on that committee. International organizations, governmental and non-governmental, in liaison with ISO, also take part in the work. ISO collaborates closely with the International Electrotechnical Commission (IEC) on all matters of electrotechnical standardization.

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This document was prepared by Technical Committee ISO/TC 172 *Optics and photonics*, Subcommittee SC 7, *Ophthalmic optics and instruments*.

This third edition cancels and replaces the second edition (ISO 10939:2007), of which it constitutes a minor revision with the following changes:

- technical correction of inconsistency in [Table 1](#), Item No. 9 “Slit image”: “Parallelism of the sides (for a slit image of 0,2 mm × 8,0 mm)”;
- update of the dated normative reference to IEC 60601-1:2005 to include the Amendment AMD1: 2012, where appropriate.

Ophthalmic instruments — Slit-lamp microscopes

1 Scope

This document, together with ISO 15004-1 and ISO 15004-2, specifies requirements and test methods for slit-lamp microscopes to provide slit illumination and observation under magnification of the eye and its adnexa.

This document is not applicable to microscope accessories, e.g. photographic equipment and lasers.

This document takes precedence over ISO 15004-1 and ISO 15004-2, if differences exist.

2 Normative references

The following documents are referred to in the text in such a way that some or all of their content constitutes requirements of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

ISO 15004-1, *Ophthalmic instruments — Fundamental requirements and test methods — Part 1: General requirements applicable to all ophthalmic instruments*

ISO 15004-2:2007, *Ophthalmic instruments — Fundamental requirements and test methods — Part 2: Light hazard protection*

IEC 60601-1:2005+AMD1:2012, *Medical electrical equipment — Part 1: General requirements for basic safety and essential performance*

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